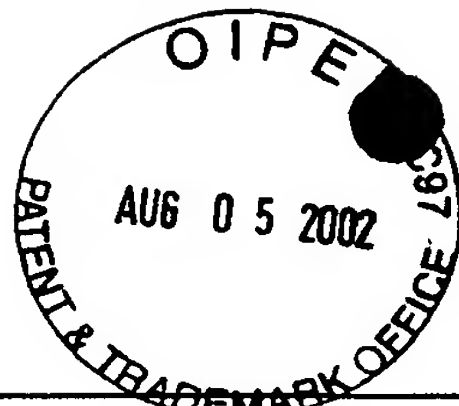




<b>Form PTO-1449 Modified</b>  List of Patent and Publications Cited by Applicant (Use several sheets if necessary)  U.S. Department of Commerce Patent and Trademark Office		Docket No. <b>UPN-4110</b>	Serial No. <b>10/052,024</b>
		Applicant <b>Dawn A. Bonnell, et al.</b>	
		Filing Date <b>January 18, 2002</b>	Group <b>Not Yet Assigned</b>
<b>OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)</b>			
WB	AA	Semancik, S. et al., "Kinetically controlled chemical sensing using micromachined structures", <i>Acc. Chem. Res.</i> , <b>1998</b> , 31, 279-287	
WB	AB	Hagfeldt, M. et al., "Molecular Photovolataics", <i>Acc. Chem Res.</i> , <b>2000</b> , 33, 269-277	
* WB	AC	<del>Hench, L.L. et al., <i>Principles of Electronic Ceramics</i>, <b>1990</b>, Wiley Interscience, New York</del>	
* WB	AD	<del>Buchanan, R., <i>Ceramic Materials for Electronics</i>, <b>1991</b>, Marcel Dekker, Inc., New York</del>	
* WB	AE	<del>Levinson, L.M. <i>Electronic Ceramics: Properties: Devices and Applicatons</i>, <b>1988</b>, Marcel Dekker, Inc., New York</del>	
* WB	AF	<del>Macdonald, I.R., <i>Impedance Microscopy: Emphasizing Solid Materials and Systems</i>, <b>1987</b>, John Wiley, New York</del>	
WB	AG	Hong, B.S. et al., "Equilibrium electrical property measurements in electroceramics", <i>Key Engineering Materials</i> , <b>1997</b> , (125-126), 163-186	
WB	AH	Jiang, S.P. et al., "Electrochemical techniques in studies of solid ionic conductors", <i>Key Engineering Materials</i> , <b>1997</b> , (125-126), 81-132	
WB	AI	Hari, N.S. et al., "Complex impedance analyses of n-BaTiO <sub>3</sub> ceramics showing positive temperature coefficient of resistance", <i>Journal of Materials Science in Electronics</i> , <b>1997</b> , 8, 15-22	
WB	AJ	Waser, R. et al., "Grain boundaries in dielectric and mixed-conducting ceramics", <i>Acta Mat</i> , <b>2000</b> , 48, 797-825	
EXAMINER <i>Walter Bmn</i>		DATE CONSIDERED <i>November 25, 2002</i>	

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<b>OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)</b>			
WP	AK	Fleig, J. et al., "Microcontact impedance measurements of individual highly resistive grain boundaries: General aspects and application to acceptor-doped SrTiO <sub>3</sub> ", <i>Journal of Applied Physics</i> , <b>2000</b> , 87(5), 2372-2381	
WP	AL	Kim, S.H. et al., "Influence of defect segregation on the electrical properties on Nb-doped SrTiO <sub>3</sub> grain boundary layer", <i>Jpn. J. Appl. Phys.</i> , <b>2000</b> , 39, 1788-1795	
WP	AM	Skapin, A.S. et al., "Grain boundary conductance in AgCl gained by micro-contact impedance spectroscopy", <i>Solid State Ionics</i> , <b>2000</b> , 133, 129-138	
WP	AN	Hwang, J.H. et al., "ingle grain boundary characterization of Nb-doped SrTiO <sub>3</sub> bicrystals using ac four-point impedance spectroscopy", <i>Applied Physics Letters</i> , <b>2000</b> , 76, 2621-2623	
WP	AO	Tanaka, S. et al., "Direct measurements of voltage-current characteristics of single grain boundary of ZnO varistors", <i>Journal of the European Ceramic Society</i> , <b>1999</b> , 19, 727-730	
WP	AP	Kalinin, S.V. et al., "Surface potential at surface-interface junctions in SrTiO <sub>3</sub> bicrystals", <i>Physical Review B</i> , <b>62(15)</b> , 10 419-10 430, <b>2000</b>	
WP	AQ	Huey, B.D. et al., "Spatially localized dynamic properties of individual interfaces in semiconducting oxides", <i>Applied Physics Letters</i> , <b>2000</b> , 76(8), 1012-1014	
* WP	AR	<del>Bonnell, D.A. et al., <i>Polycrystalline Semiconductors VI-Bulk Materials, Thin Films, and Devices</i></del>	
WP	AS	Williams, C.C. "Two-dimensional dopant profiling by scanning capacitance microscopy", <i>Annu. Rev. Mat Sci.</i> , <b>1999</b> , 29, 471-504	
WP	AT	De Wolf, P. et al., "One- and two-dimensional carrier profiling in semiconductors by nanospredding resistance profiling", <i>J. Vac. Sci. Technol</i> , <b>1996</b> , 14(1), 380-385	
EXAMINER <i>Walter Brown</i>		DATE CONSIDERED <i>November 25, 2003</i>	

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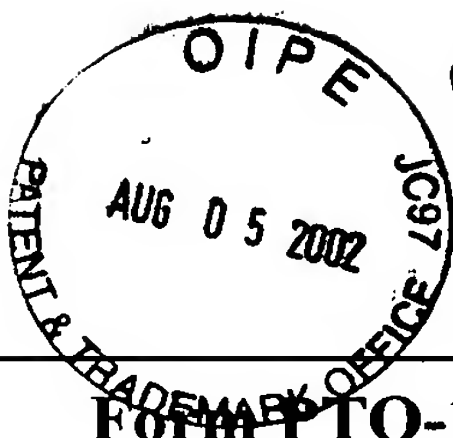
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<b>OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)</b>			
WB	AU	Oyama, Y, et al., "Analysis of scanning probe used for simultaneous measurement of tunneling current and surface potential", <i>Journal of Applied Physics.</i> , 1999, 86(12), 7087-7093	
WB	AV	Stranick, S.J. et al., "A versatile microwave-frequency-compatible scanning tunneling microscope", <i>Rev. Sci. Instrum.</i> , 1993, 64(5), 1232-1234	
WB	AW	Cho, Y. et al., "Scanning nonlinear dielectric microscope", <i>Rev. Sci. Instr.</i> , 1996, 67(6), 2297-2303	
* WB	AX	Chaikin, P.M. et al., <i>Principles of Condensed Matter Physics</i> , 1997, Cambridge University Press, New York	
* WB	AY	Sarid, D., <i>Scanning Force Microscopy</i> , 1991, Oxford University Press, New York	
WB	AZ	Kim, S.H. et al., "Effect of MnO addition on the electrical properties of Nb-doped SrTiO <sub>3</sub> varistor", <i>Materials in Science &amp; Engineering.</i> , 1999, 56, 12-20	
WB	BA	Pike, G.E. "Semiconductor grain boundary admittance: Theory", <i>Phys. Rev.</i> , 1984, 30, 795-802	
WB	BB	Blatter, G, "Electrical breakdown at semiconductor grain boundaries", <i>Phys. Rev. B.</i> , 1986, 34(12), 8555-8572	
WB	BC	Babcock, K. et al., "Magnetic force microscopy: Recent advances and applications", <i>Matter. Res. Soc. Syrup. Proc.</i> , 1995, 355, 311-323	
EXAMINER <i>Walter R. [Signature]</i>		DATE CONSIDERED <i>November 25, 2003</i>	

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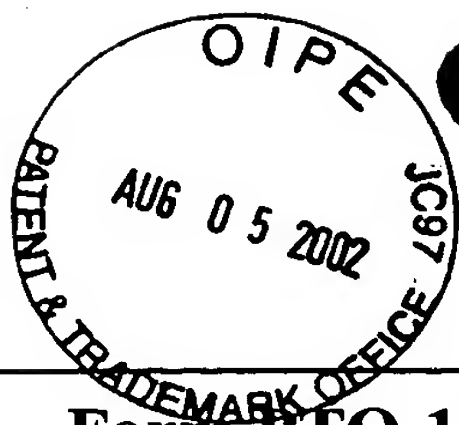
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<b>OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)</b>			
WB	BD	Zhong, Q. et al., "Fractured polymer/silica fiber surface studied by tapping mode atomic force microscopy", <i>Surface Science Letters</i> , 1993, 290, L688-L692	
* WB	BE	<del>Wiesendanger, R., <i>Scanning Probe Microscopy: Methods and Applications</i>, 1994, Cambridge University Press, New York</del>	
* WB	BF	<del>Sarid, D., <i>Scanning Force Microscopy</i>, 1991, Oxford University Press, New York</del>	
WB	BG	Rice, P., et al., "Observation of the effects of tip magnetization states on magnetic force microscopy images", <i>J. Appl. Phys.</i> , 1999, 85(8), 5163-5165	
WB	BH	Ferrier, R.P. et al., "Characterisation of MFM tip fields by electron tomography", <i>IEEE Transactions on Magnetism</i> , 1997, 33(5), 4062-4064	
WB	BI	Hug, H.J. et al., "Quantitative magnetic force microscopy on perpendicularly magnetized samples", <i>J. Appl. Phys.</i> , 1998, 83(11), 5609-5620	
WB	BJ	Ishii, I. et al., "A novel numerical approach to interpret images obtained by magnetic force microscope", <i>IEEE Transactions on Magnetism</i> , 1998, 34(5), 3455-3458	
WB	BK	Saito, H. et al., "Description of magnetic force microscopy by three-dimensional tip Green's function for sample magnetic charges", <i>Journal of Magnetism &amp; Magnetic Materials</i> , 1999, 191, 153-161	
EXAMINER <i>Walter Brown</i>		DATE CONSIDERED <i>November 25, 2002</i>	

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<b>OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)</b>			
WB	BL	Tomilson, S.L. et al., "Micromagnetic model for magnetic force microscopy tips", <i>J. Appl. Phys.</i> , 1997, 81(8), 5029-5031	
WB	BM	Al-Khafaji, M.A., "Magnetic force microscopy of nanocrystalline NdFeB ribbons: A study of tip-sample interaction using a well-characterised sample", <i>Journal of Magnetism &amp; Magnetic Materials</i> , 1998, 182, 111-123	
WB	BN	Hartmann, U., "The point dipole approximation in magnetic force microscopy", <i>Physics Letters A.</i> , 1989, 137(9), 475-478	
WB	BO	Hartmann, U., "Magnetic force microscopy", <i>Annu. Rev. Mater Sci.</i> , 1999, 29, 53-87	
WB	BP	Kong, L. et al., "Quantification of magnetice force microscopy using a micronscale current ring", <i>Appl. Phys. Lett</i> , 1997, 70(15), 2043-2045	
WB	BQ	Hartmann, U., "Theory of magnetic force microscopy", <i>J. Vac. Sci. Technol.</i> , 1990, 8(1), 411-415	
WB	BR	Lohau, J. et al., "Quantitative determination of effective dipole and monopole moments of magnetic force microscopy tips", <i>J. Appl. Phys.</i> , 1999, 86(6), 3410-3417	
* WB	BS	<del>Jackson, J.D., <i>Classical Electrodynamics</i>, 1998, (Wiley, New York)</del>	
* WB	BT	<del>Chaikin, P.M. et al., <i>Principles of Condensed Matter Physics</i>, 1997, Cambridge University Press, New York</del>	
EXAMINER <i>W. B.</i>		DATE CONSIDERED <i>November 25 2003</i>	

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<b>OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)</b>			
WB	BU	Weaver, J.M.R. et al., "High resolution atomic force microscopy potentiometry", <i>J. Vac. Sci. Technol.</i> , 1991, 9, 1559-1561	
WB	BV	Nonnenmacher, M. et al., "Kelvin probe force microscopy", <i>Appl. Phys. Lett.</i> , 1991, 58(25), 2921-2923	
<b>EXAMINER</b> <i>Walt Rm</i>		<b>DATE CONSIDERED</b> <i>March 25, 2003</i>	

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List of Patent and Publications  
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U.S. Department of Commerce  
Patent and Trademark Office

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**UPN-4110**

Serial No.  
**10/052,024**

Applicant  
**Dawn A. Bonnell, et al.**

Filing Date  
**January 18, 2002**

Group  
**Not Yet Assigned**

**U. S. PATENT DOCUMENTS**

Examiner Initial		Document No.	Date	Name	Class	Subclass
WB	BW	5,308,974	05/03/94	Elings, et al.	250	234
WB	BX	5,266,801	11/30/93	Elings, et al.	250	306

**FOREIGN PATENT DOCUMENTS**

Examiner Initial		Document No.	Date	Country	Translation	
					YES	NO

**EXAMINER***Walter R...***DATE CONSIDERED***November 25, 2002*